

## AD571 Qualification Data

<b>QUALIFICATION RESULTS</b>			
<b>TEST</b>	<b>CONDITIONS</b>	<b>SAMPLE SIZE</b>	<b>RESULTS</b>
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	<b>9 lots of 45</b>	<b>Pass</b>
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	<b>9 lots of 45</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>9 lots of 45</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>3 lots of 45</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>6</b>	<b>Pass</b>
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JDS-001-2011</i>	<b>3/voltage</b>	<b>Pass 1500V</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>3/voltage</b>	<b>Pass 250V</b>

\*Preconditioned per JEDEC/IPC J-STD-020 MSL 1